

Notice of References Cited	Application/Control No. 10/039,279	Applicant(s)/Patent Under Reexamination YAVATKAR ET AL.	
	Examiner Venkatesh Haliyur	Art Unit 2664	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,763,018	07-2004	Puthiyandil et al.	370/352
	B	US-5,790,546	08-1998	Dobbins et al.	370/400
	C	US-2002/0103631	08-2002	Feldmann et al.	703/22
	D	US-6,091,732	07-2000	Alexander et al.	370/401
	E	US-6,081,522	06-2000	Hendel et al.	370/389
	F	US-6,404,735	06-2002	Beshai et al.	370/230
	G	US-2003/0016664	01-2003	MeLampy et al.	370/389
	H	US-2002/0136202	09-2002	Droz et al.	370/352
	I	US-6,954,463	10-2005	Ma et al.	370/401
	J	US-6,370,584	04-2002	Bestavros et al.	709/238
	K	US-2003/0023701	01-2003	Norman et al.	709/214
	L	US-2002/0103921	08-2002	Nair et al.	709/232
	M	US-2002/0099849	07-2002	Alfieri et al.	709/243

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.